

L Number	Hits	Search Text	DB	Time stamp
1	194	werner-brian\$	USPAT	2003/07/24 09:24
2	4	werner-brian\$ and simulation and resist	USPAT	2003/07/24 10:17
3	26	("4628531" "4633504" "4641353" "4669123" "4958374" "5023328" "5293557" "5307421" "5475766" "5481624" "5513275" "5572598" "5582939" "5621652" "5633713" "5736280" "5745388" "5801954" "5804340" "5849440" "5889678" "5889686" "5965306" "6014456" "6067375" "6081659").PN.	USPAT	2003/07/24 09:24
4	1	6272236.URPN.	USPAT	2003/07/24 09:59
5	5	6091845.URPN.	USPAT	2003/07/24 10:00
6	1516	(382/141-151).CCLS.	USPAT	2003/07/24 10:17
7	0	("6 and display\$5 with superimpos\$5 with image").PN.	USPAT	2003/07/24 10:18
8	24	((382/141-151).CCLS.) and display\$5 with (overlap\$5 or superimpos\$5) near image	USPAT	2003/07/24 10:18
15	16	wafer same (superimpos\$5) same width same area	USPAT	2003/07/24 10:28
16	6	wafer and display\$5 near (superimpos\$5) and width same area	USPAT	2003/07/24 11:05
19	0	analyze near defects same (area and width)	USPAT	2003/07/24 11:06
20	1243	(analyze or analysis or characteriz\$5) near defects	USPAT	2003/07/24 11:07
21	1243	(analyze or analysis or characteriz\$5) near defect	USPAT	2003/07/24 11:07
23	1	((analyze or analysis or characteriz\$5) near defect) same (line near width) same area	USPAT	2003/07/24 11:07
22	26	((analyze or analysis or characteriz\$5) near defect) and (line near width) same area	USPAT	2003/07/24 13:21
24	0	defect with percentage with area with difference	USPAT	2003/07/24 13:23
25	250	percentage with area with difference	USPAT	2003/07/24 13:23
27	0	(percentage with area with difference) and inspectionwafer	USPAT	2003/07/24 13:24
26	9	(percentage with area with difference) and wafer	USPAT	2003/07/24 13:24
28	19	(percentage with area with difference) and inspection	USPAT	2003/07/24 13:25
29	0	("6 and (percent\$5 or "%") with difference with area").PN.	USPAT	2003/07/24 13:26
30	0	((382/141-151).CCLS.) and (percent\$5 or "%") with difference with area	USPAT	2003/07/24 13:27
31	8	((382/141-151).CCLS.) and (percent\$5 or "%") with area	USPAT	2003/07/24 13:28
32	9	(percent\$5 or "%") near difference with area	USPAT	2003/07/24 13:36
33	0	(percent\$5 or "%") near difference with overall near area	USPAT	2003/07/24 13:34
34	32	(percent\$5 or "%") near difference same area	USPAT	2003/07/24 13:35
35	23	((percent\$5 or "%") near difference same area) not ((percent\$5 or "%") near difference with area)	USPAT	2003/07/24 13:35
36	2	(percent\$5 or "%") near difference with defect	USPAT	2003/07/24 13:36
37	98	(percent\$5 or "%") near difference with area	USPAT	2003/07/24 13:38
38	2	((percent\$5 or "%") near difference with area) same defect	USPAT	2003/07/24 13:37
39	5	((percent\$5 or "%") near difference with area) and inspect\$5	USPAT	2003/07/24 13:37
40	0	(percent\$5 or "%") near difference with (overlap\$5 or superimpos\$5) near area	USPAT	2003/07/24 13:38
42	848193	area near ratio with (template or reference)t	USPAT	2003/07/24 13:39
43	23	(area near ratio with defect) and (area near ratio with (template or reference)t)	USPAT	2003/07/24 13:40
44	413	area near ratio with (template or reference)	USPAT	2003/07/24 13:40
45	1	(area near ratio with defect) and (area near ratio with (template or reference))	USPAT	2003/07/24 13:40
41	41	area near ratio with defect	USPAT	2003/07/24 13:46
46	0	area with percent\$5 with defect	USPAT	2003/07/24 13:46

47	133	area with percent\$5 with defect	USPAT	2003/07/24 13:47
48	47	(area with percent\$5 with defect) and image	USPAT	2003/07/24 13:47
-	194	werner-brian\$	USPAT	2003/07/24 09:24
-	29	werner-brian\$ and simulat\$6	USPAT	2003/07/23 15:55
-	1	("6091845").PN.	USPAT	2003/07/23 15:55